

Resource Summary Report

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FEI: Helios Nanolab 600i DualBeam

RRID:SCR_027033

Type: Tool

Proper Citation

FEI: Helios Nanolab 600i DualBeam (RRID:SCR_027033)

Resource Information

URL: <https://www.microscop.ru/uploads/Helios-NanoLab-600i-ds-web.pdf>

Proper Citation: FEI: Helios Nanolab 600i DualBeam (RRID:SCR_027033)

Description: Scanning Electron Microscope advanced DualBeam for ultra-high resolution imaging, analysis and fabrication at the nanoscale. Helios NanoLab 600i builds on the success of FEI's winning DualBeam series offering advances in ion beam, electron beam, patterning and range of features to make milling, imaging, analysis and sample preparation down to nanoscale.

Synonyms: FEI Helios NanoLab 600i DualBeam, , FEI Helios NanoLab 600i DualBeam Scanning Electron Microscope, Helios NanoLab 600i

Resource Type: instrument resource

Keywords: Scanning Electron Microscope, imaging, analysis, nanoscale, microscope, electron microscope,

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_027033.pdf

Resource Name: FEI: Helios Nanolab 600i DualBeam

Resource ID: SCR_027033

Alternate IDs: Model_Number_Helios_NanoLab_600i

Record Creation Time: 20250606T053416+0000

Record Last Update: 20260912T200517+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Helios Nanolab 600i DualBeam.

No alerts have been found for FEI: Helios Nanolab 600i DualBeam.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.